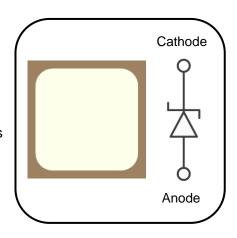


3rd Generation 650V/50A SiC Schottky Barrier Diode

Features

- Revolutionary semiconductor material Silicon Carbide (SiC)
- No reverse recovery
- > High-speed switching performance
- > Temperature-independent switching behavior
- System cost / size savings due to reduced cooling requirements
- ➤ Junction temperature range from -55°C to 175°C
- RoHS compliant



Potential Applications

- Industrial power supplies: Industrial UPS
- Battery chargers
- Solar inverters
- Switch mode power supplies



Description

The SDS065J050B3 SiC Schottky Barrier Diode (SBD) has been developed using Sanan's advanced 3rd generation SiC SBD technology with the highest performance and reliability. It registers higher efficiency, higher operation temperature and lower loss and can be operated at higher frequency than Si-based solutions. As to the Schottky structure, it shows no recovery at turn-off and allows a low leakage current with reverse voltage up to 650V. It can contribute to system miniaturization and achieve lightweight system design. Using RoHS compliant components, it is qualified for use in industrial application.

Product Specifications

Device	V _{RRM}	I _F (135°C)	V _F (25°C)	Qc
SDS065J050B3	650V	57A	1.35V	138nC



CONTENTS

Features	1
Potential Applications	1
Description	1
Product Specifications	1
Table 1. Maximum Ratings	3
Table 2. Thermal Resistance	3
Table 3. Static Electrical Characteristics	4
Table 4. Dynamic Electrical Characteristics	4
Electrical Characteristic Diagrams	5
Ordering Information	6
Important Notices – Read Carefully	7
Warning	7



Table 1. Maximum Ratings

(Tc = 25°C, unless otherwise specified)

Parameter	Symbol	Value	Unit	Test conditions		
Repetitive peak reverse voltage	V_{RRM}	650		T _C = 25°C		
Surge peak reverse voltage	V_{RSM}	650	V	$T_C = 25^{\circ}C$		
DC reverse voltage	V_{DC}	650		$T_C = 25^{\circ}C$		
		111		$T_C = 25^{\circ}C$		
Continuous forward current	I _F	57	А	T _C = 135°C		
		50		T _C = 145°C		
Surge non-repetitive forward current	I _{FSM}	360	Α	$T_C = 25$ °C, $t_p = 10$ ms, half sine pulse		
Repetitive peak forward current	I _{FRM}	229	Α	$T_C = 25$ °C, $t_p = 10$ ms, half sine wave D = 0.1		
i²t value	∫i²dt	567	A ² s	$T_C = 25^{\circ}C$, $t_p = 10ms$		
Operating junction temperature	Tj	-55~175	°C			
Storage temperature	T _{stg}	-55~175	°C			

Table 2. Thermal Resistance

Dovementer	Cumbal	,	Values		Unit	Test
Parameter	Symbol	Min. Typ.	Max.	condition		
Thermal resistance from junction to case	R _{th(j-c)}	/	0.43	/	°C/W	

^{*}Thermal Resistance is collected in TO247-2L

Table 3. Static Electrical Characteristics

(Tc = 25°C, unless otherwise specified)

Devementer	Symbol	Values			1 1 1 2 1 4	Took conditions
Parameter		Min.	Тур.	Max.	Unit	Test conditions
DC blocking voltage	V_{DC}	650	/	/	V	I _R = 100 μA
	V _F	/	1.35	1.50	>	$I_F = 50A, T_j = 25^{\circ}C$
Forward voltage		/	1.55	1.80		$I_F = 50A, T_j = 175$ °C
		/	5	100		$V_R = 650V, T_j = 25^{\circ}C$
Reverse current	I _R	/	25	250	μA	$V_R = 650V, T_j = 175$ °C

Table 4. Dynamic Electrical Characteristics

(Tc = 25°C, unless otherwise specified)

Barrantan	Ob-all	Values			1111	T
Parameter	Symbol		Max.	Unit	Test conditions	
		/	2850	/		$V_R = 0V$, $f = 1MHz$
Total capacitance	С	/	254	/	pF	V _R = 200V, f = 1MHz
		/	220	/		$V_R = 400V, f = 1MHz$
Total capacitive charge	Q _C	/	138	/	nC	V _R = 400V
Capacitance stored energy	Ec	/	20	/	μJ	V _R = 400V



Electrical Characteristic Diagrams

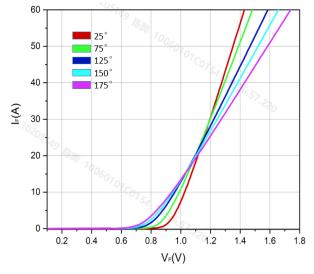


Figure 1. Forward characteristics

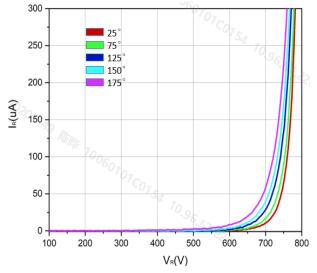


Figure 2. Reverse characteristics

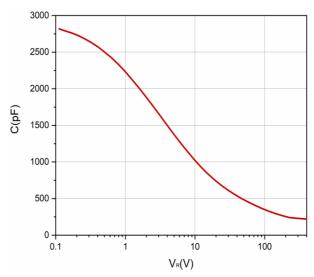


Figure 3. Capacitance vs. reverse voltage

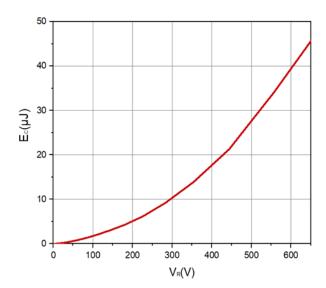


Figure 4. Capacitance stored energy



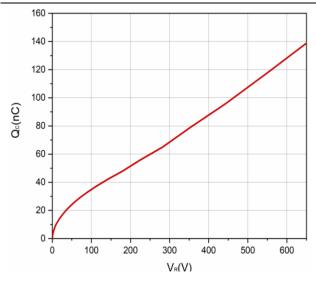


Figure 5. Total capacitance charge vs. reverse voltage

Ordering Information

Part Number	SDS065J050B3		
Package	Bare Die		
Packing Method	Wafer		
RoHS	Yes		

Important Notices - Read Carefully

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